

Advanced Thermal Management

Cooling of Power Electronics (e.g., Inverters or Converters)

Introduction

Power electronic systems such as inverters and converters are essential in renewable energy setups, electric vehicles, motor drives, and industrial power conversion applications. These systems rely on semiconductor devices (IGBTs, MOSFETs, SiC/GaN switches) that operate at high frequencies and handle significant power levels. During operation, conduction and switching losses convert electrical energy into heat at the semiconductor junctions.

If this heat is not removed effectively, device temperatures rise, reducing efficiency, accelerating degradation, and risking thermal runaway.

Thermal management therefore becomes a core design requirement and not just a secondary consideration.

Scope of the report

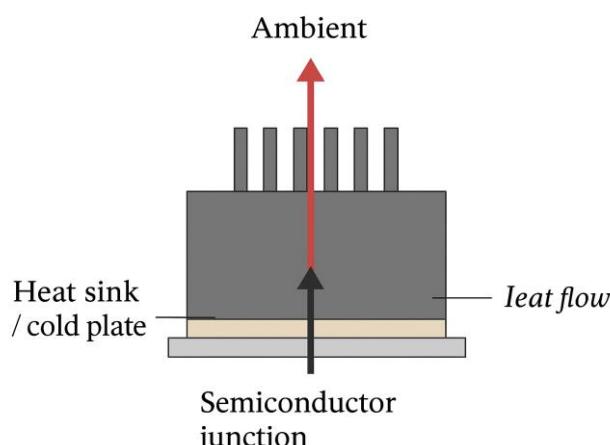
This report explains heat generation mechanisms in power electronic modules, heat flow paths, thermal interfaces, cooling techniques (air cooling, liquid cooling, cold plates, phase change materials), and a focused case example involving a three-phase inverter module. It also highlights the connection between thermodynamics principles and electrical engineering performance.

Objectives

1. To describe the major thermal phenomena and loss mechanisms in power-electronic modules.
2. To discuss modern cooling methods and compare their suitability for various applications.
3. To present a focused case example demonstrating thermal calculations and design decisions.

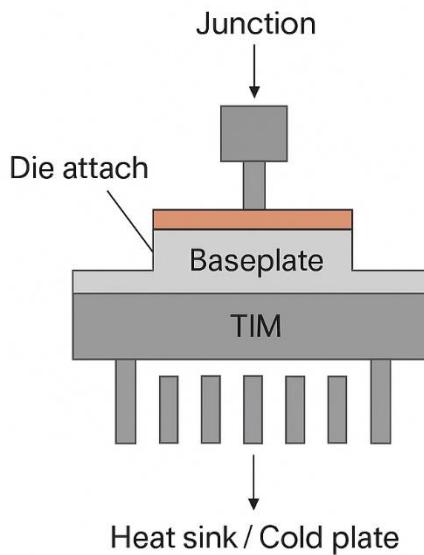
Link Between Thermodynamics and Electrical Engineering

- **Energy and heat transfer:** Electrical losses convert directly into heat. Steady state heat removal must match this loss power to keep the junction temperature within limits.
- **Losses and efficiency:** High temperatures increase conduction and switching losses, lowering system efficiency. Proper cooling pushes the system toward lower entropy generation and better performance.
- **Energy conversion and management:** Thermal resistance networks, Fourier's law, and convection equations allow engineers to predict temperatures and design optimized cooling paths for stable operation.



Key Equations

Heat generated (steady-state)	$\dot{Q}_{loss} = P_{loss}$
Fourier's Law (conduction)	$q = -kA \frac{dT}{dx}$
Thermal resistance model	$R_{th,ja} = \frac{T_j - T_a}{P_{loss}}$
Convective heat transfer	$\dot{Q}_{conv} = hA(T_s - T_a)$
Energy absorbed by coolant (liquid cooling)	$\dot{Q} = \dot{m}c_p(T_{out} - T_{in})$



Thermal Behaviour and Cooling Strategies (Discussion)

1. Heat Generation in Power Electronic Devices

Power electronic switches (IGBTs, MOSFETs, SiC/GaN devices) experience two unavoidable loss mechanisms: **conduction losses** and **switching losses**.

Conduction losses arise from on state resistance or voltage drop, typically expressed as

$$P_{cond} = I^2 R_{on} \quad (\text{MOSFETs}), \quad P_{cond} = V_{CE(sat)} \cdot I \quad (\text{IGBTs})$$

Switching losses occur when voltage and current overlap during turn on and turn off events, and they increase with switching frequency. These losses convert directly into heat at the semiconductor junction, forming the primary thermal load in power converters.

High temperature operation increases carrier mobility effects, leakage currents, and switching times, meaning that thermal management directly influences efficiency and reliability.

Semiconductor datasheets specify maximum junction temperature limits (often 125 – 175 °C for silicon and up to 200+ °C for SiC), and cooling systems are designed to maintain operation below these limits.

2. Heat Flow Path and Thermal Resistance Network

The heat produced at the junction travels through several layers before reaching ambient conditions. The standard thermal pathway includes:

- Semiconductor junction → die attach → substrate (DBC) → baseplate
- Thermal Interface Material (TIM) → heat sink or cold plate → ambient air/coolant

This chain is modelled using a thermal resistance network, where each layer contributes a resistance $R_{th,i}$.

The total thermal resistance from junction to ambient is:

$$R_{th,ja} = R_{th,jc} + R_{th,cs} + R_{th,sa}$$

where $R_{th,jc}$ is junction to case, $R_{th,cs}$ is case to sink (TIM), and $R_{th,sa}$ is sink to ambient.

A lower overall resistance results in a smaller temperature rise for the same power loss:

$$T_j = T_a + P_{loss} \cdot R_{th,ja}$$

These relationships form the foundation of power electronics thermal design and are standard in thermodynamics and heat transfer literature.

3. Cooling Methods Used in Power Electronics

a) Passive Cooling (Natural Convection Finned Heat Sinks)

Passive cooling relies on buoyancy driven airflow. It is reliable and silent but has low heat transfer coefficients (typically 5 – 25 W/m²·K). This method suits low to medium power converters or systems where simplicity is a priority.

b) Forced Air Cooling

Fans increase airflow velocity, raising the convective heat transfer coefficient (50 – 250 W/m²·K). This method is widely used in industrial inverters and motor drives.

Thermal design focuses on fin geometry, air channel spacing, and maintaining acceptable pressure drop.

c) Liquid Cooling (Cold Plates)

Liquid cooled cold plates provide much higher heat flux removal due to the large specific heat of liquids and stronger convection coefficients (500 – 10,000 W/m²·K depending on design).

Coolants such as water glycol mixtures absorb heat according to:

$$\dot{Q} = \dot{m}C_p(T_{out} - T_{in})$$

Liquid cooling is essential in EV traction inverters, high density server power supplies, and renewable-energy converters.

d) Advanced and Emerging Techniques

Phase change materials, heat pipes, vapor chambers, and jet impingement cooling are increasingly used for high switching frequency designs and SiC/GaN converters where heat fluxes are higher. These methods rely on phase change thermodynamics and two-phase convection to achieve very high heat transfer rates.

4. Reliability Factors and Thermal Cycling

Power modules experience repetitive thermal cycles as load varies, causing expansion and contraction of solder joints, bond wires, and substrates. Thermomechanical stress can eventually lead to microcracks, delamination, or bond-wire lift-off.

Thermal cycling lifetime is strongly affected by peak junction temperature, temperature swing ΔT , and dwell time all governed by fundamental thermodynamic and material property behaviour.

Focused Case: Thermal Management of a Three-Phase Inverter Module

1. Selected Device: IGBT-Based Three-Phase Inverter Module

Three-phase inverters are used in motor drives, renewable energy converters, and EV traction systems. A typical inverter module contains six switching devices (IGBTs or MOSFETs) arranged in a half-bridge configuration for each phase. Each switch experiences conduction and switching losses that vary with load, modulation index, and switching frequency.

For the case study, we consider a **typical 1200 V / 100 – 200 A industrial IGBT module** mounted on an aluminium heat sink or liquid cooled cold plate.

2. Loss Estimation (Example)

Device datasheets provide turn on / turn off energy values (E_{on} , E_{off}) and conduction characteristics at reference temperatures.

At a switching frequency f_s , the total switching loss is approximately:

$$P_{sw} = (E_{on} + E_{off})f_s$$

Conduction loss is:

$$P_{cond} = V_{CE(sat)} \cdot I_{avg}$$

For a typical mid power inverter, total device loss per switch often falls in the **10 - 60 W** range depending on load and switching frequency. Multiplied across all six switches, total module losses can reach **100 – 300 W**, all of which must be dissipated through the thermal path.

3. Thermal Path Calculation (Illustrative)

Assume the module datasheet gives:

- $R_{th,jc} = 0.15 \text{ K/W}$
- TIM resistance $R_{th,cs} = 0.10 \text{ K/W}$
- Heat-sink/ambient resistance $R_{th,sa} = 0.30 \text{ K/W}$

Total thermal resistance:

$$R_{th,ja} = 0.15 + 0.10 + 0.30 = 0.55 \text{ K/W}$$

If the inverter dissipates **180 W** under rated load:

$$\Delta T = P_{loss} \cdot R_{th,ja} = 180 * 0.55 \approx 99^\circ C$$

If ambient temperature is

- $T_a = 25^\circ C$

Then:

$$T_j = 25 + 99 = 124^\circ C$$

This is within typical IGBT safe limits ($\sim 150^\circ C$), but leaves limited margin.

Such calculations guide whether:

- A more conductive TIM is needed
- Fin geometry must be improved
- Liquid cooling should replace air cooling

4. Why Many Systems Use Liquid Cooling

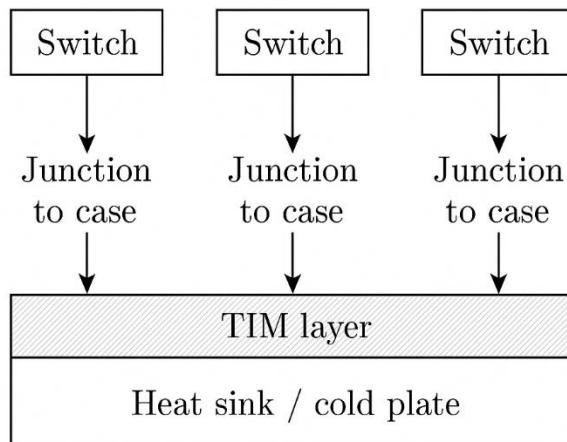
As switching frequencies increase (especially with SiC devices), heat flux density rises sharply. Air cooling struggles with high power density because of its low heat transfer coefficient. Liquid cooling provides:

- Higher (h) values
- Lower overall thermal resistance
- Stable thermal performance even under transient surges

A standard cold-plate system with water-glycol may achieve:

$$R_{th,sa} < 0.1 \text{ K/W}$$

reducing junction temperatures by **20 – 40 °C** for the same load.



Conclusion

Power electronic devices generate significant heat due to conduction and switching losses. Without effective thermal management, junction temperatures can exceed safe limits, reducing efficiency, reliability, and lifetime.

Thermal pathways from the semiconductor junction to ambient including die attach, TIM, baseplate, and heat sinks or cold plates must be optimized using principles from thermodynamics and heat transfer. Both passive and active cooling techniques have strengths and limitations, with liquid cooling increasingly necessary for high density, high frequency systems.

Focused analysis of a three-phase inverter module illustrates how thermal resistance calculations guide design decisions, ensuring junction temperatures remain within safe limits. Linking thermodynamic analysis with electrical-engineering constraints allows engineers to manage energy, reduce losses, and optimize performance in power electronic systems.

References

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